INSPECTION SYSTEM AND METHOD FOR DETERMINING THE MICROSTRUCTURE FOR A COATING

ABSTRACT

A method for determining a microstructure of a coating on a component. The method includes projecting at least a first electromagnetic signal in a first plane of polarization onto the coating and a second electromagnetic signal in a second plane of polarization onto the coating. A first and second time delay can be determined. The microstructure of the coating is based on a difference between at least two time delays.

[FIG. 2, FIG. 12]